Search Notes

Application/Control No.
10/621,111
Examiner
Kimbinh T. Nguyen

Applicant(s)/Patent under Reexamination
FENNEY ET AL.
Art Unit

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	SEARCHED					
Class	Subclass	Date	Examiner			
345	419	8/5/2006	KN			
345	420	8/5/2006	KN			
345	427	8/5/2006	KN			
382	232	8/5/2006	KN			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
345	420	8/5/2006	KN		
345	427	8/5/2006	KN		
382	232	8/5/2006	KN		
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WEST: text search	8/5/2006	KN
NPL: ACM, IEEE	. 8/5/2006	KN
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